

**WHAT IS CLAIMED IS:**

1    1. A semiconductor memory device comprising:  
2         an input pin row including a plurality of input  
3         pins;  
4         an output pin row including a plurality of output  
5         pins;  
6         a memory cell array including a plurality of cell  
7         plates in a plurality of cell columns between the input  
8         and output pin rows;  
9         a plurality of sense amplifiers in two amplifier  
10      columns disposed between the adjacent two of the  
11      plurality of cell columns;  
12      an address circuitry;  
13      an address transition detector (ATD) circuitry to  
14      provide an ATD pulse upon detecting a transition in the  
15      address circuitry;  
16      an ATD pulse synthesizer to provide a synthesized  
17      pulse in response to the ATD pulse;  
18      an output circuitry; and  
19      a delay circuitry to provide a sense amplifier data  
20      latch signal and an output data latch signal in response  
21      to the synthesized pulse from the ATD pulse synthesizer,  
22      at least the address, ATD and delay circuitries  
23      being disposed between the input pin row and the  
24      plurality of cell columns,  
25      the ATD pulse synthesizer being disposed between  
26      the two amplifier columns and spaced a predetermined  
27      signal transmission path from the ATD and delay  
28      circuitries.

1    2. The semiconductor memory device as claimed in claim  
2    1, further comprising:  
3         an error correction code (ECC) circuitry disposed

4    between the two amplifier columns together with the ATD  
5    pulse synthesizer, and the delay circuitry provides an  
6    ECC data latch signal.

1    3.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein said output circuitry is disposed between  
3    the two amplifier columns and between the ATD pulse  
4    synthesizer and the output pin row.

1    4.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein said output circuitry is disposed between  
3    the cell columns and the output pin row.

1    5.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein the device has write function.

1    6.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein the address, ATD and delay circuitries  
3    only are disposed in a site between the input pin row and  
4    the plurality of cell columns.

1    7.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein the number of the plurality of cell plates  
3    is four.

1    8.   The semiconductor memory device as claimed in claim  
2    1 or 2, wherein the output pin row includes at least one  
3    input pin.

1    9.   The semiconductor memory device as claimed in claim  
2    1 or 2,  
3        wherein each of the plurality of cell columns  
4    include a plurality pairs of cell plates, and  
5        further comprising:

6        a plurality of X-decoders, each disposed between  
7        the cell plates of one of the plurality of pairs;  
8        a plurality of Y-select circuits, each disposed  
9        between an inner side of the cell plates of one of the  
10      plurality of pairs and the adjacent sense amplifier of  
11      one of the amplifier columns; and  
12      a plurality of X-predecoders, each disposed  
13      adjacent an outer side of the cell plates of one of the  
14      plurality of pairs.

1        10. The semiconductor memory device as claimed in claim  
2        1 or 2, wherein the memory cell array includes a plurality  
3        of horizontal digit lines, and a plurality of vertical  
4        word lines.